

PROPOSED AMENDMENT TO THE CLAIMS:

Please cancel claims 30-31, 33-49, 56, and 58-60 without prejudice:

1 – 49. (Cancelled)

50. (Previously Presented) A method for testing an optoelectronic device, comprising:

- a) making contact between an external control and an arrangement of test contact areas which are larger than operational contact areas;
- b) providing an input terminal of a drive circuit directly or via another component with input signals via the arrangement of test contact areas to generate a test pattern on a matrix of picture elements, wherein the drive circuit is provided with signals for picture generation during operation via the operational contact areas connected to the input terminal of the drive circuit, the drive circuit comprises the input terminal for receiving external signals, means for modifying the external signals to form modified signals, and means for providing the modified signals for the matrix of picture elements during normal operation and during test mode; and
- c) testing the picture elements of the matrix of picture elements.

51. (Previously Presented) The testing method according to claim 50, wherein:
the input signals generate a periodic test pattern.

52. (Previously Presented) The testing method according to claim 50, wherein:
the input signals generate a vertically, horizontally or diagonally periodic test pattern.

53. (Previously Presented) The testing method according to claim 50, wherein:
the picture elements are tested with a beam of charged particles or laser radiation.

54. (Previously Presented) The testing method according to claim 50, comprising the further step of:

a vacuum is generated in the vicinity of the optoelectronic device to be tested.

55. (Previously Presented) The testing method according to claim 50, wherein step c) comprises the following steps:

c1) testing the picture elements in a portion of the matrix of picture elements;

c2) shifting the optoelectronic device; and

c3) testing the picture elements in a further portion of the matrix of picture elements.

56. (Cancelled)

57. (Previously Presented) An optoelectronic device, which has been tested by a testing method according to claim 50 or by an apparatus according to claim 30.

58 - 60. (Cancelled)